

## CHIPLINK N-Channel Enhancement Mode Power MOSFET

### Description

The LX3030N combines advanced trench technology to provide excellent  $R_{DS(ON)}$ , it tailored to minimize conduction loss, and provide superior switching performance. It can be used in wide variety of application.

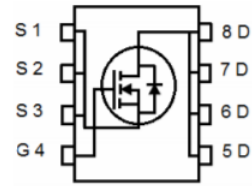
### Features

- $V_{DS}=30V$ ,  $I_D=30A$   
 $R_{DS(ON)typ.}=9.0m\Omega@V_{DS}=10V$   
 $R_{DS(ON)typ.}=12.5m\Omega@V_{DS}=4.5V$
- Fast switching
- High power and current handing capability
- Termination is Lead-free and RoHS Compliant

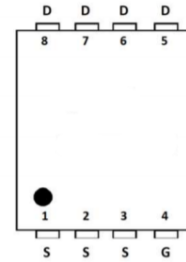


### Applications

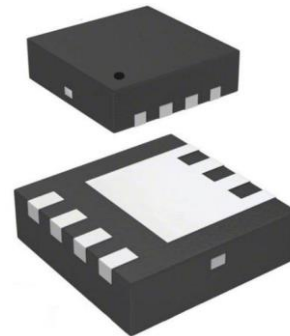
- PWM applications
- Load switch
- Power Management



Schematic Diagram



Pin Assignment



DFN3\*3 Package

### Maximum Ratings( $T_A=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D(T_C=25^\circ C)$	30	A
	$I_D(T_C=100^\circ C)$	20	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	120	A
Maximum Power Dissipation <sup>A</sup>	$P_D$	9	W
Single pulse avalanche energy	$E_{AS}$	36	mJ
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 To 150	$^\circ C$

## Thermal Characteristic

Thermal Resistance, Junction to Case	$R_{QJA}$	6.5	$^{\circ}\text{C/W}$
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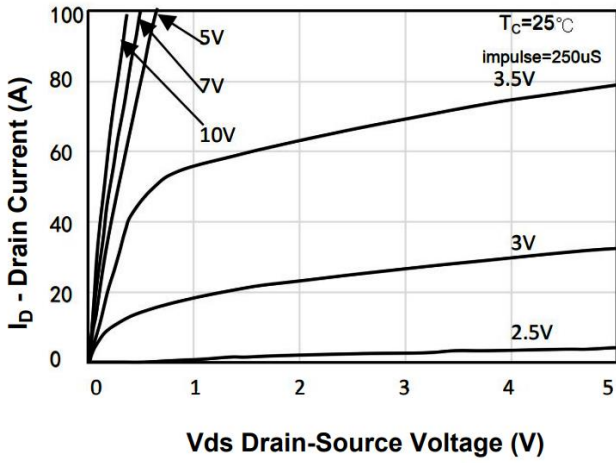
## Electrical Characteristics ( $T_A=25^{\circ}\text{C}$ unless otherwise specified)

Parameter	Symbol	Test conditions	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0V, I_D=250\mu A$	30			V
Gate-Threshold Voltage	$V_{th(GS)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1	1.5	2.2	V
Gate-body Leakage	$I_{GSS}$	$V_{DS}=0V, V_{GS}=\pm 12V$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=30V, V_{GS}=0V$			1	$\mu A$
Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=5A$		9	13	m $\Omega$
		$V_{GS}=4.5V, I_D=4A$		12.5	17	m $\Omega$
Forward Transconductance	$g_{FS}$	$V_{DS}=5V, I_D=5A$	10			s
<b>Dynamic Characteristics</b>						
Input Capacitance	$C_{iss}$	$V_{DS}=15V, V_{GS}=0V, F=1\text{MHz}$		865		pF
Output Capacitance	$C_{oss}$			105		
Reverse Transfer Capacitance	$C_{rss}$			86		
<b>Switching Capacitance</b>						
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=15V, R_L=3\Omega, V_{GS}=10V, R_{GEN}=3\Omega$		5		nS
Turn-on Rise Time	$t_r$			4		nS
Turn-off Delay Time	$t_{d(off)}$			22		nS
Turn-off Fall Time	$t_f$			6		nS
Total Gate Charge	$Q_g$	$V_{DS}=15V, I_D=5A, V_{GS}=4.5V$		18		nC
Gate-Source Charge	$Q_{gs}$			3		nC
Gate-Drain Charge	$Q_{gd}$			5		nC
<b>Drain-Source Diode Characteristics</b>						
Diode Forward Voltage	$V_{SD}$	$V_{GS}=0V, I_D=5A$			1.2	V
Diode Forward Current	$I_S$				30	A

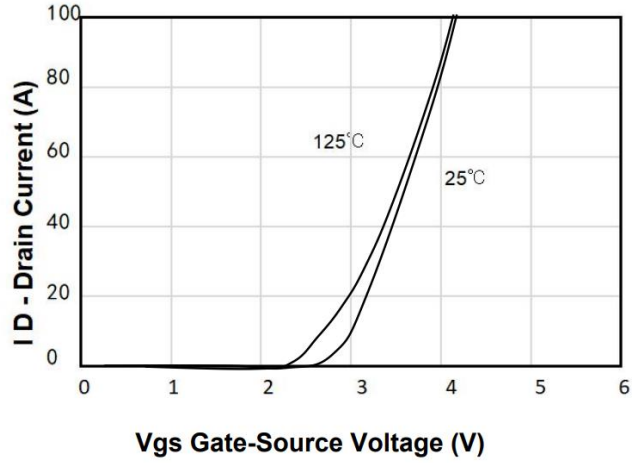
### Notes:

- The Power dissipation  $P_D$  is based on  $T_{J(MAX)}=150^{\circ}\text{C}$ , using  $\leq 10\text{s}$  junction-to ambient thermal resistance.
- Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)}=150^{\circ}\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^{\circ}\text{C}$ .
- The Static characteristics in Figures are obtained using  $< 300\mu\text{s}$  pulses, duty cycle 2% max.
- EAS condition:  $T_J=25^{\circ}\text{C}, V_{DD}=15V, V_{GS}=10V, R_G=25\Omega, L=0.5\text{Mh}, I_{AS}=19A$ .

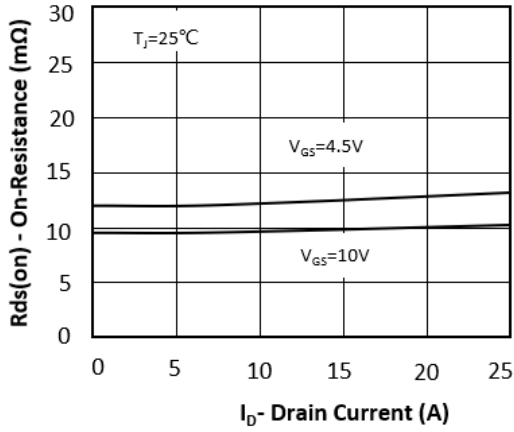
**Typical Electrical and Thermal Characteristics**



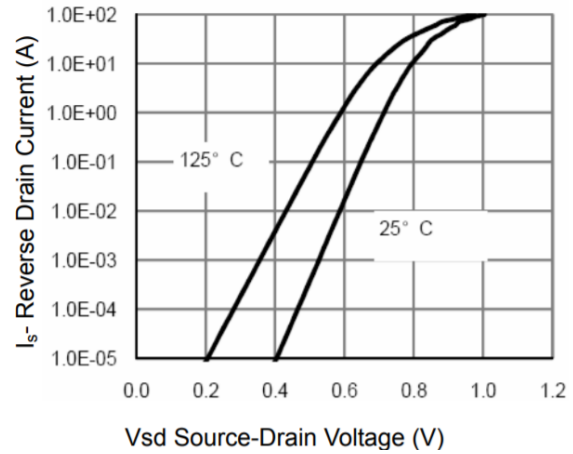
**Figure 1. On-Region Characteristics**



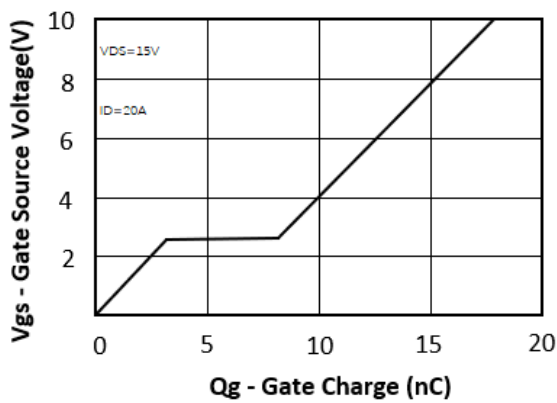
**Figure 2. Transfer Characteristics**



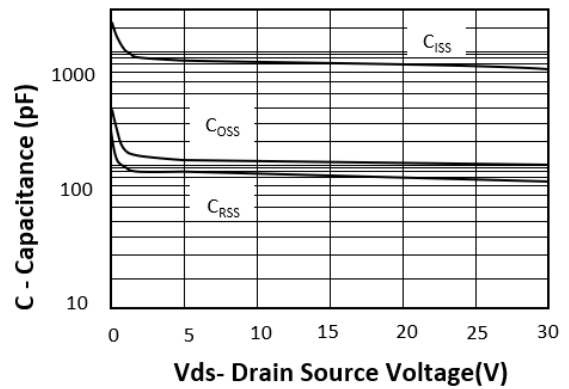
**Figure 3. On-resistance vs. Drain Current**



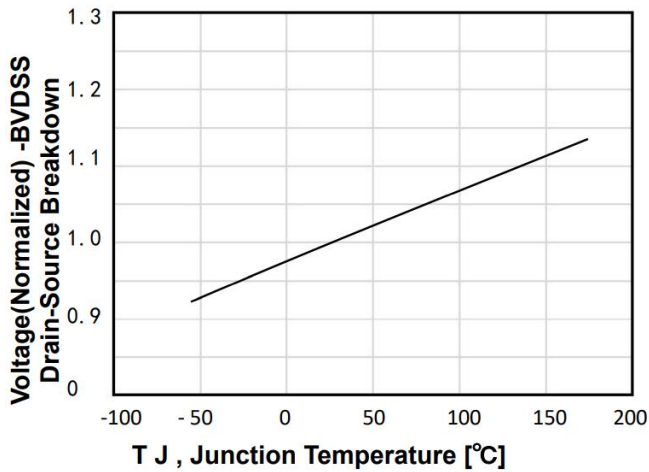
**Figure 4. Body Diode Characteristics**



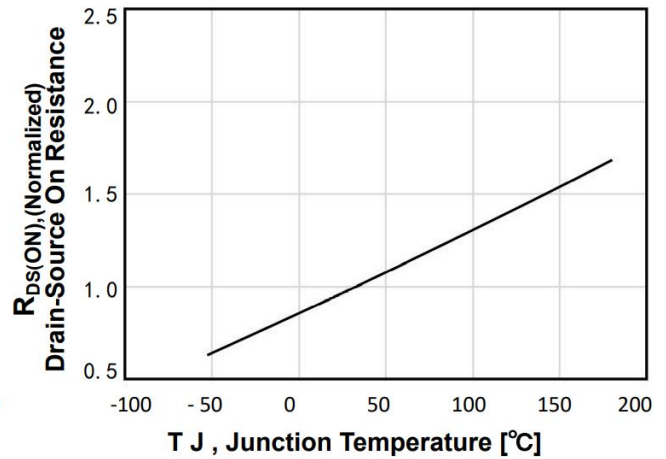
**Figure 5. Gate Charge Characteristics**



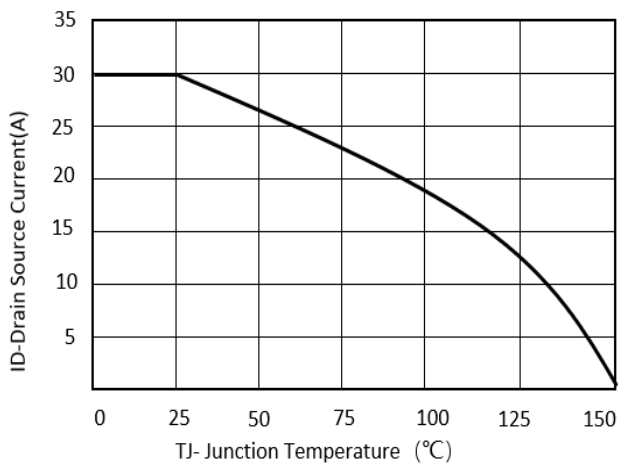
**Figure 6. Capacitance Characteristics**



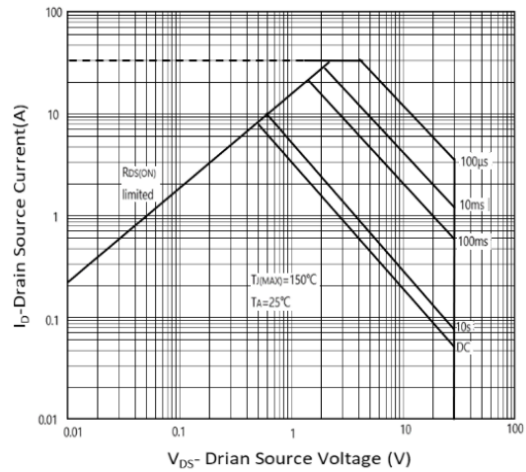
**Figure 7. Breakdown Voltage Variation vs Temperature**



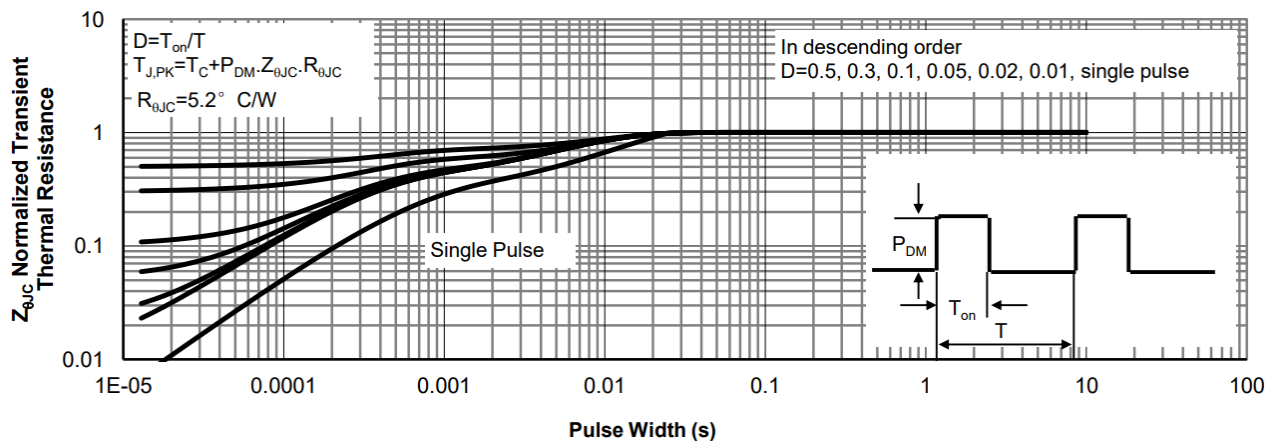
**Figure 8. On-Resistance Variation vs Temperature**



**Figure 9. Current - Junction Temperature**

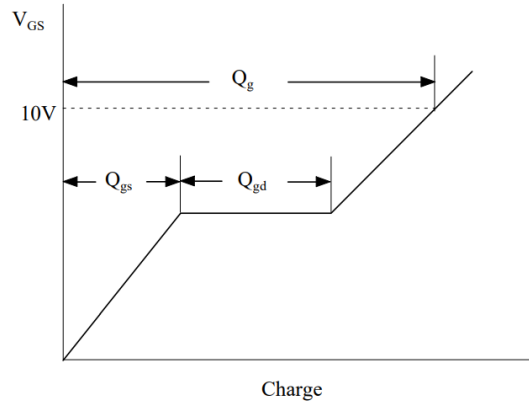
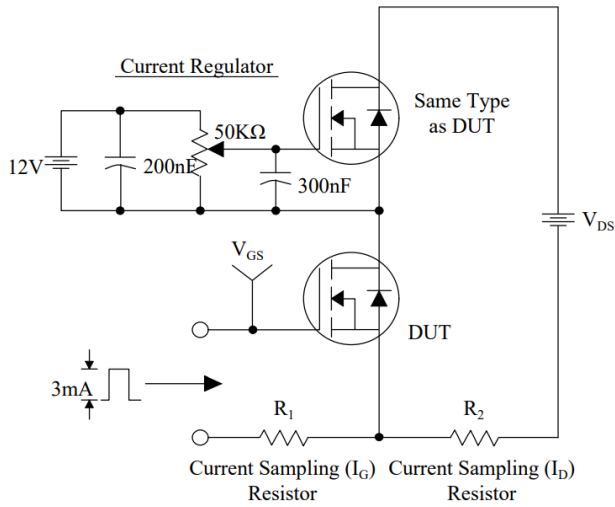


**Figure 10. Safe Operation Area**

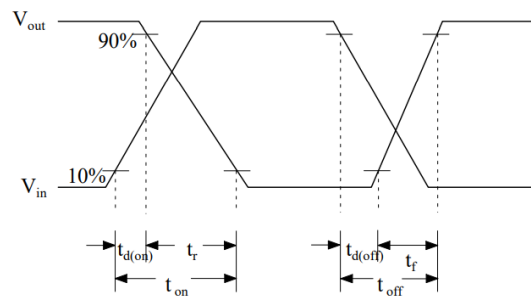
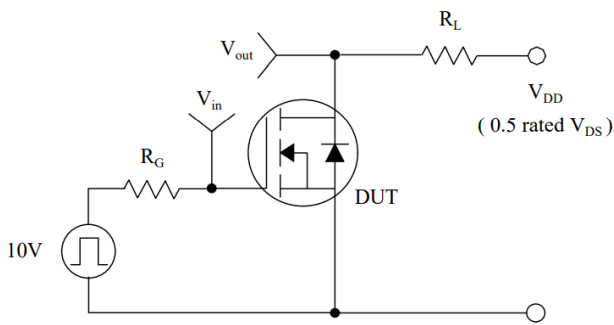


**Figure 11. Normalized Maximum Transient Thermal Impedance**

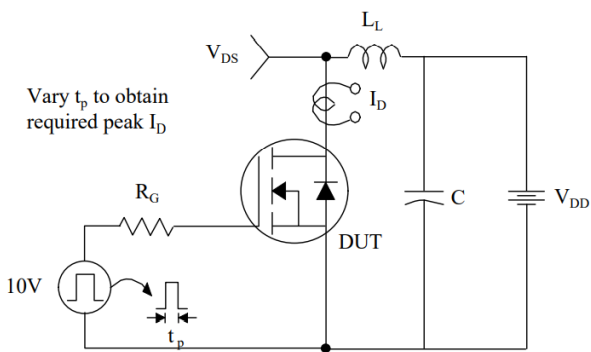
### Gate Charge Test Circuit & Waveform



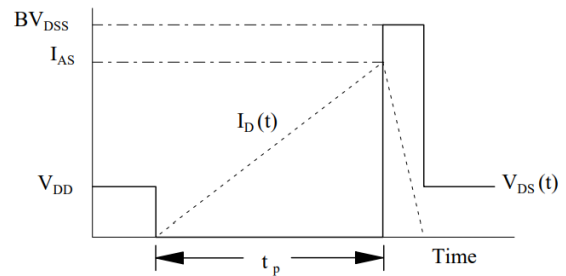
### Resistive Switching Test Circuit & Waveforms



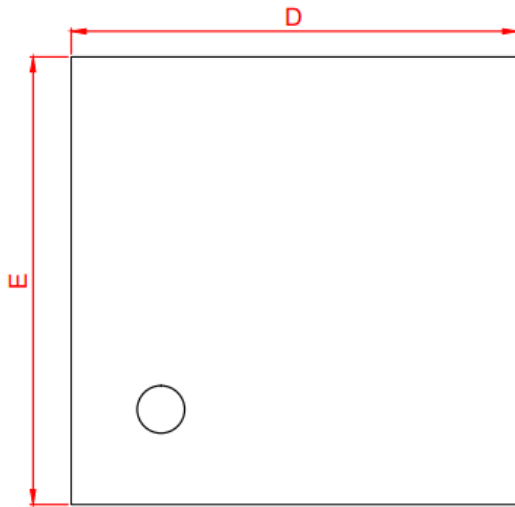
### Unclamped Inductive Switching Test Circuit & Waveforms



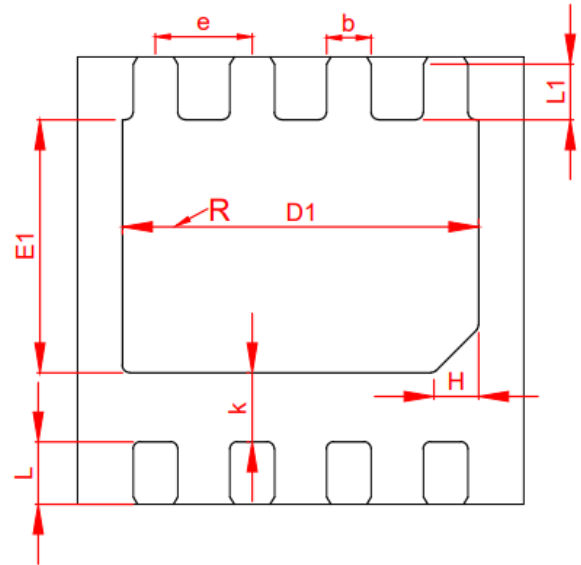
$$E_{AS} = \frac{1}{2} L_L I_{AS}^2$$



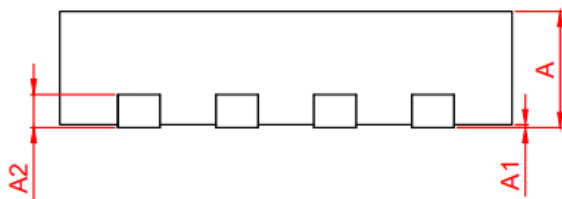
**DFN3\*3 Package Information**



TOP VIEW



BOTTOM VIEW



SIDE VIEW

SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	0.70	0.75	0.80
* A1	0.00	0.02	0.05
* b	0.27	0.32	0.37
* A2	0.20REF		
* D	2.90	3.00	3.10
* E	2.90	3.00	3.10
* E1	1.70	1.80	1.90
* D1	2.35	2.45	2.55
* e	0.65BSC		
* L	0.35	0.40	0.45
h	0.30 REF		
* k	0.50REF		
* L1	0.25	0.30	0.35

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